

## Patent Assignment Abstract of Title

**Total Assignments: 1**

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**PCT #:** NONE **Publication #:** 20020144200 **Pub Dt:** 10/03/2002  
**Inventors:** Takehiko Shimomura, Masayuki Konishi  
**Title:** Scan test system for semiconductor device

**Assignment: 1**

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**Conveyance:** ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).

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